F iske steps studied with ux-ow resistance oscillation in a narrow stack of B i_2Sr_2C aC u_2O_{8+d} junctions

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We have experimentally investigated the uxon dynamics in a narrow $Bi_2Sr_2CaCu_2O_{8+d}$ stack with junction length L 1.8 m. As an evidence of high-frequency excitation by a collective cavity mode, under an (in-plane) external magnetic eld, the current-voltage characteristics show prominent Fiske steps with the corresponding resonance frequencies of 75-305 G Hz. Further study of ux- ow resistance oscillation with various c-axis currents clari es the correlation with Fiske steps by distinguishing two dimensions i.e., static ux- ow region at low bias current level and dynamic Fiske step region at high bias current level.

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In stacked $B_{12}Sr_2CaCu_2O_{8+d}$ (BSCCO) intrinsic Josephson junctions (IJJs), the mutual interaction between junctions is expected since the superconducting layers, with the layer thickness d = 0.3 nm, are much thinner than the London penetration depth $_L = 170$ nm¹. Under the applied magnetic eld parallel to the layers, Josephson vortices in a stack form lattice con gurations that depend on a constant phase shift between neighboring layers, ranging from 0 for the rectangular lattice to for the triangular lattice (see Fig.1(a))^{2,3,4}.

Under the appropriate conditions, the uxon lattice will excite the two-dimensional cavity modes in N stacked junctions, leading to the emission of electrom agnetic wave with characteristic frequency $f_{nm} \quad m \ c_n = 2L$ (c_n is the phase velocity of electrom agnetic wave, L is the junction length, m (= 1, 2, 3, \ldots) denotes L-direction mode, and n (= 1, 2, 3, \ldots N) denotes the stacking direction mode)⁵. The c_n is given by

$$c_n = !_{n1,J} [1 \quad 2S \cos(n = (N + 1))]^{1=2};$$
 (1)

with the Josephson penetration depth $_{\rm J}$, the coupling parameter S, the junction number N and the Josephson plasm a frequency $!_{\rm pl}{}^{1,2,5}$. Am ong the N di erent modes along the stacking direction, the mode with the lowest velocity $q_{\rm N}$ is usually stimulated by a triangular vortex lattice; while for the mode with the highest velocity $c_{\rm l}$, a rectangular lattice is favorable^{6,7}.

Being driven by a c-axis bias current, the moving uxon lattice generates ux- ow resistance (FFR) in the junctions. Recent experimental^{8,9,10} and numerical^{11,12} studies show that the motion of traveling uxon lattice in the layers is rejected into the periodic oscillation of FFR under the low bias current by considering the dynamicalmatching between the vortex lattice and the sample

edges. The H₀=2-period oscillation of FFR is interpreted as a result of the form ation of triangular lattice in a longjunction stack, where H $_{0}$ is the eld for adding one ux quantum per one junction (H $_{0}$ $_0$ =Ls, $_0$ being the ux quantum and s the layer periodicity along the c axis ie. 1.5 nm)^{8,11}. Recent studies indicate that when the junction size is reduced down to a few m and approaches the short-junction stack lim it (L < J), the oscillation period becom es predom inantly H $_0$ rather than H $_0$ =2 due to the deformation of the Josephson vortex lattice by strong interaction with junction edges9,10. The result m ay suggest a possible existence of collective vortex m otion such as a rectangular vortex lattice in a narrow stack. However the recent FFR research is limited at very low bias current levels such as less than 1% of critical current at zero eld I_{c0}, and it is still obscure whether the vortex dynam ics studied by FFR is related with high-frequency excitation or not.

In this paper, stim ulated by the above-mentioned researches, we can ne ourselves to study of the singularities in the I V curves and the correlation with the currentdependent FFR oscillation in the narrow BSCCO stacks with L 1.8 m and large junction number N >> 1, exploring the high-frequency excitation by a possible collective uxon motion.

In our experiments, a BSCCO whisker¹³ with a clean and at surface was fabricated to be an in-line type of IJJs stack with the length of 1.8 m by a focused ion beam. A schematic diagram of the stack is shown in the inset of Fig. 1 (b). Here, L and D denote the junction length perpendicular to the magnetic eld and the depth parallel to the eld. The fabricated IJJs stack had a thickness of about 180 nm, i.e., containing about 120 junctions. The values of critical tem perature (T_c) was 81

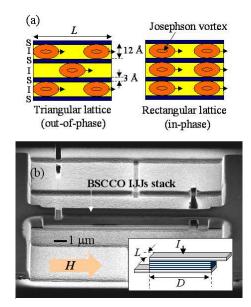


FIG.1: (Color online) (a) The con gurations of Josephson vortex lattice in a stacked BSCCO IJJs. The triangular lattice corresponds to the out-of-phase case, while the rectangular lattice corresponds to the in-phase situation. (b) Scanning ion-beam microscope in age of BSCCO stack fabricated by the focused ion beam etching. Schem atic diagram of the stack is shown in the inset. M agnetic eld H was applied along the longer side (D) of junction to enhance edge e ect.

K, and the values of I_{c0} were about 350 A at 10 K and about 195 A at 50 K respectively. The electric transport properties were measured with a four-term inal con guration using a Physical Property M easurement System (PPM S, Quantum Design), which can supply magnetic

eld up to 9 T. In order to enhance the edge e ect of the sam ple on m oving Josephson vortices, we applied the m agnetic eld parallel to the ab-plane along the longer side (D) of the BSCCO stack (see Fig. 1 (b)). The sam – ple was m ounted on a rotatable holder with a resolution better than 0.005° . The in-plane alignm ent was precisely adjusted by the angular dependence of FFR under externalm agnetic eld.

The Josephson penetration depth $_{\rm J}$ is given by $_{\rm J} = [_{0}=2 _{0} j_{\rm c} (t_{\rm eff} + 2 ^{2}=d_{\rm eff})]^{1=2}$ with the e ective values $d_{\rm eff} = \sinh(d=)$, $t_{\rm eff} = t + 2 \tanh(d=2)$, the $(in_{\rm c}plane)$ magnetic penetration depth $(T) = _{ab}(0) = 1 (T=T_{\rm c})^{4}$, by assuming $_{ab}(0) = 170$ nm, the thickness of superconducting layers and insulating layers d= 0.3 nm and t= 1.2 nm¹⁴. The $_{\rm J}$ of our sample was calculated as 0.27 m at 10 K (0.34 m at 50 K). The sam ple width of 1.8 m is about 6.6 tim es (about 5.3 tim es at 50 K) as large as the calculated $_{\rm J}$ at 10 K, thus it can be still regarded as a long-junction stack; how ever, as we applied magnetic elds perpendicular to the narrow er side, which is di erent from the conventional case, we use the term harrow 'to specify our sample.

Figure 2 (a) displays the I V characteristics under various m agnetic elds parallel to the layers at 50 K. In or-

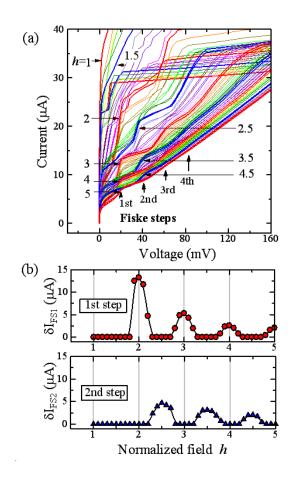


FIG. 2: (Color online) (a) I V characteristics at various elds from 0.765 T (h = 1) to 3.825 T (h = 5) with an interval of 0.0765 T (0.1 h) at 50 K.Bold lines show I V curves at elds h = integer and half integer where F iske steps are clearly observed. (b) The magnetic eld dependence of the current am plitudes of rst step and second step at 50 K.

der to indicate a periodic m odulation of the I V curves with eld, we norm alized the magnetic elds in graphs of Fig. 2 by the period $H_P = 0.765 \text{ T}$, which corresponds to H_0 calculated for this sample. Then we can regard the norm alized eld h $H = H_P$ (= $H = H_0$) as Josephson uxon num ber per unit junction. The magnetic eld was applied in the range from 0.765 T (h = 1) to 3.825 T (h = 5) with an interval of 0.0765 T (0.1h).

W ith increasing magnetic eld, we found clear current steps that were regularly developed in the I V curves, as shown in F ig. 2 (a). These steps were identi ed as F iske steps that had been observed as a strong enhancement of superconducting current when the Josephson frequency (! = $2eV=\sim$) m atches the resonant frequency of electrom agnetic cavity m odes excited in junctions^{15,16,17,18}. The asym ptotic voltage positions of step series are given by

$$V = m N (_{0}C_{n} = 2L):$$
 (2)

U sing the voltage position of the $\,$ rst F iske step (18.7 m V) de ned by localm axim um dI/dV, the characteristic

velocity was estimated to be $c_n = 2.71 \quad 10^5 \text{ m/sec}$ using Eq. (2) with m = 1, N = 120, and L = 1.8 m. Since the series of F iske steps are observable up to the 4th order in F ig. 2 (a), the corresponding resonance frequency lies in the range of 75–305 G H z.

A coording to Eq. (1), using a set of the experimental parameters (the current density j_c =1.015 kA/cm 2 at 50 K, the thickness of insulating layer t=1.2 nm, the coupling constant S $\,$ 0.5, and $_{\rm J}$ =0.76 m), the velocities of the lowest mode and the highest mode are calculated as c_{120} =2.62 $\,10^5$ m/sec and $c_{\rm l}$ =1.86 $\,10^7$ m/sec, respectively. Our result, estimated from the Fiske step, is comparable with the velocity of the lowest collective cavity resonance mode, in agreement with Refs. 17 and 18.

The observed odd and even steps obviously have di erent dependences on the magnetic eld. Fig. 2(b) shows the eld dependence of the step height ($I_{\rm FS}$) for the rst and second steps. W ith increasing eld, each height of the rst and the second order steps oscillated with the same period H₀. However, the maxima of the rst order step appeared at h= integer, and the minima at h= halfinteger; while the second order step exhibited opposite behavior. Note that this is very similar to the behavior of a single junction^{15,16} except that large current-step voltage due to the contribution from all junctions. This is very important because such a single junction behavior is possible when all junctions are evenly excited by a collective cavity resonance in stacked junctions.

For further understanding of F iske steps, we also studied the correlation between F iske steps and the FFR oscillation as function of magnetic eld, which has been regarded as a powerful tool for this purpose^{8,9,10,11,12}.

At extremely low c-axis current I = 1 A (0.52 % of I_{c0}), as shown in Fig. 3, there are two oscillation regimes of FFR :one is below h = 2.5 and the other is over h = 2.5 with the oscillation period of H $_0$ (see Part A and B in Fig. 3). The details for the change in oscillation period by magnetic eld will be elucidated with the model based on the edge current elsew here¹⁰.

Having noticed in Fig. 2(a), there is not any step at such a low current level, we intended to measure the FFR at much high current levels. Surprisingly, we have observed a new anom aly of FFR oscillation at higher bias currents as shown in Fig. 3. In particular, for high eld h > 25 (Part B in Fig. 3) it is found that the peaks and the local minim a of FFR oscillation were inverted by varying bias current as marked by the arrows, with the oscillation period H $_0$ unchanged. Note that the inversion from the peaks to the localm in in a of FFR oscillation in plies a change of the matching between the edge and Josephson vortices as well as an enhanced conductance. As is well known, such conductance enhancement in a Josephson junction, usually resulting from resonance in the junction, should manifest itself as a current steps in the I V characteristics.

To con m this, we compared the current-dependent anomaly of FFR oscillation in Fig. 3 with the I V curves

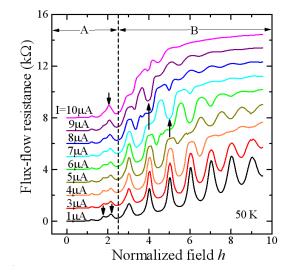


FIG.3: (Color online) FFR anom alies due to c-axis bias current of 1-10 A at 50 K, where each curve is shifted by 1 k for clarity. The magnetic elds are normalized by H $_{\rm p}$ = 0:765 T.W ith increasing current, there are two kinds of features; Part A: two small peaks transform to one peak with period H $_0$ at h < 2.5. Part B: the inversion from peaks to local m inimum s at h > 2.5. The dash dot line in Part B shows the boundary of two di erent regimes with c-axis bias current.

in Fig. 2(a). Looking at the FFR curves marked by the arrows at the normalized eld h = 4 and 5 in Fig. 3, the clear inversion from peaks to local minima took place when the bias current was varied from 5 A to 9 A. Considering the corresponding curves in Fig. 2(a) with the same eld and bias current range, we see two Fiske steps appearing at the same voltage in the I V curves, as marked by the arrows at the elds h = 4 and 5. As one can see in Fig. 3, there are several more inversion points at di erent normalized elds, and the corresponding steps in Fig. 2(a).

D i erent from the high eld regin e h > 2.5 where the FFR oscillates with the period H₀, in the low eld regin e h < 2.5 where the FFR oscillation period is smaller than H₀ and comparable with H₀=2, there is neither inversion of the FFR oscillation nor steps up to 10 A. In the case of the eld of h = 2 in Fig. 2(a), the rst Fiske step appears at the current around 20 A. The experimental results show the inversion of FFR oscillation near 20 A after FFR becom es H₀-oscillation, i.e., two peaks merge into one peak (see the arrows in Part A of Fig. 3). A c-cordingly, it is clear that the Fiske steps appear only in the regime that FFR oscillates with a period of H₀ and that there is the inversion of FFR oscillation from peaks to localm inim a.

N oticeably, after the inversion of FFR oscillation, there is distortion of H $_0$ -oscillation with I=8 A around h=4 and h=4.5 where the rst and the second steps appear in I V curves. This can be understood with the following explanation. When the rst and the second Fiske steps coexist at same current level, FFR will relate the behav-

ior of these Fiske steps under magnetic eld. Then the product of two (odd and even step's) eld dependence factors (refer to Fig. 2 (b)) should consequently result in H₀=2-period oscillation of FFR. This is in fact the case at which U stinov and Pedersen could observe H₀=2-oscillation in their simulation for a single long-junction¹⁹. However in our experiments, some steps don't coexist at the same current due to large voltage intervals between Fiske steps and the reduced step amplitude at 50 K. Therefore the FFR oscillation was mainly a ected from one step (odd or even), with the dom inant H₀-period at the current near Fiske steps. Nevertheless, the neighboring steps caused observable distortion of FFR.

Having understood the correlation between the FFR oscillation and the I V characteristics, we can distinguish between the two di erent regimes divided by dash dot line in Part B of Fig. 3. In the low bias region before the occurrence of inversion of FFR, i.e., before the appearance of Fiske steps, the Josephson uxon dynam - ics is mainly determined by the edge pinning e ect and the coupling interaction between the layers^{11,12}. Therefore the information of uxon lattice can be probed by the FFR oscillation measurement to some extent. As a matter of fact, such oscillation of FFR in this regime (especially at the low bias current and high eld) is just same as I_c modulation with magnetic eld.

On the other hand, in the inversion region of FFR oscillation accompanying the Fiske steps at relatively high bias current range, the dynamic resonant uxon motion is dominant due to the interaction between the traveling uxon and the cavity mode excitation. Thus in the high bias region showing the Fiske steps, the uxon lattice can't be determ ined simply by the measurem ent of FFR oscillation. We can only try to gure out the lattice structure by comparing the characteristic velocity obtained from the Fiske steps measurem ent and Eq. (1).

W ith low-tem perature scanning electron m icroscopy (LT SEM), Q uenter et al:²⁰ also observed sim ilar di erent regim es . For the bias points close to origin (in a nite voltage state w ithout F iske steps), the LT SEM im age showed the static distribution of the Josephson current in the presence of an external m agnetic eld. For the high bias point close to a voltage of F iske resonance, a clear standing-w ave pattern is observed due to the superposition of the traveling w ave and the re ected w aves. These are consistent w ith our results.

In summary, the current-voltage characteristics of BSCCO IJJs stacks with L 1.8 m under an externalmagnetic eld showed pronounced Fiske steps as an evidence of high-frequency excitation. The alternative appearance of even and odd F iske steps resem bles the behavior of a single junction, although there are more than 100 junctions in one stack. The observed F iske steps and theirm ode of the collective cavity resonance suggest that all junctions in such a narrow stack can be synchronized by the Fiske resonance. Further measurements on the eld-dependent FFR with various c-axis currents clarify the correlation with F iske steps by distinguishing two di erent regions i.e., static ux- ow region at low bias current level and dynam ic Fiske step region at high bias current level.

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